#### **Features**

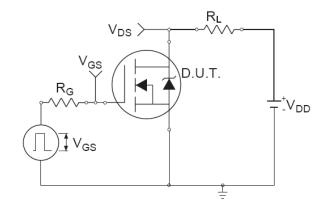
- $V_{DSS}$ =80V/ $V_{GSS}$ =±25V/ $I_{D}$ =66A  $R_{DS(ON)}$ =12m $\Omega$ (Max.)@ $V_{GS}$ =10V
- Reliable and Rugged
- Advanced trench process technology
- High Density Cell Design For Ultra Low On-Resistance

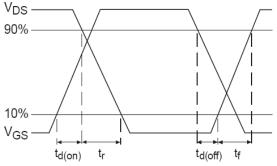
## **Applications**

- Synchronous Rectification
- Power Management in Inverter System

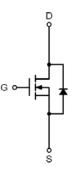
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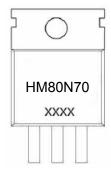
# **Switching Time Test Circuit and Waveforms**





## **Pin Description**





Marking and pin Assignment



TO-220-3L top view

#### **Package Marking and Ordering Information**

<u>~</u>					
<b>Device Marking</b>	Device	Device Package	Reel Size	Tape width	Quantity
HM80N70	HM80N70	TO-220-3L	/#/ _	-	-

"""

# $80 V_{DS}/\pm 25 V_{GS}/66 A(I_D)\,$ N-Channel Enha ncement Mode MOSFET

# Absolute Maximum Ratings (T<sub>A</sub>=25°C unless otherwise noted)

Symbol	Parameter	Typical	Unit
$ m V_{DSS}$	Drain-Source Voltage	80	V
$ m V_{GSS}$	Gate –Source Voltage		V
T	T <sub>C</sub> =100°C	46	A
$I_D$	Continuous Drain Current	66	A
$I_{DP}$	300us Pulsed Drain Current Tested T <sub>C</sub> =25°C	240	A
$I_{S}$	Diode Continuous Forward Current	66	Α
$T_{\rm J}$	Operating Junction Temperature	175	°C
$T_{STG}$	Storage Temperature Range	-55 ~ 175	°C

## **Electrical Characteristics** (TA=25°C unless otherwise noted)

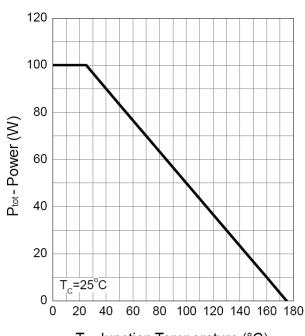
Symbol	Parameter	<b>Test Conditions</b>	Min.	Тур	Max.	Unit	
Static Char	acteristics						
$\mathrm{BV}_{\mathrm{DSS}}$	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V,I <sub>D</sub> =250uA	80			V	
ī	Zono Coto Voltogo Duoin Comment	$V_{DS}=64V, V_{GS}=0V$			1	A	
$I_{DSS}$	Zero Gate Voltage Drain Current	T <sub>J</sub> =85°C			30	uA	
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{D}=-250uA$	2	3	4	V	
$I_{GSS}$	Gate Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$			±100	nA	
$R_{DS(on)}^{1}$	Drain-Source On-Resistance	$V_{GS}=10V, I_{D}=30A$		10	12	mΩ	
<b>Diode Char</b>	acteristics						
${ m V_{SD}}^1$	Diode Forward Voltage	$I_{SD} = 20A, V_{GS} = 0V$		0.8	1.3	V	
$t_{rr}$	Reverse Recovery Time	$I_{SD}=30A$ ,		44		Ns	
$Q_{rr}$	Reverse Recovery Charge	$dI_{SD}/dt=100A/us$		60		nC	
Dynamic Cl	haracteristics <sup>2</sup>						
$R_G$	Gate Resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, Frequency=1MHz		1.5		Ω	
$C_{iss}$	Input Capacitance			2900		pF	
$C_{oss}$	Output Capacitance	$V_{GS}$ =0V, $V_{DS}$ =40V		290			
$C_{rss}$	Reverse Transfer Capacitance	Frequency=1MHz		175			
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}$ =40V, $R_L$ =30 $\Omega$		14	25		
$t_{\rm r}$	Turn-On Rise Time	$I_{D}$ =30A, $V_{GEN}$ =10V		11	20	ns	
$t_{ m d(off)}$	Turn-Off Delay Time	$R_G=6\Omega$		51	92		
$t_{\mathrm{f}}$	Turn-Off Fall Time	NG 022		22	40		
Gate Charge Characteristics <sup>2</sup>							
$Q_{g}$	Total Gate Charge	V <sub>DS</sub> =40V, V <sub>GS</sub> =10V		55	77		
$Q_{gs}$	Gate-Source Charge	$I_{D}=30A$		12		nC	
$Q_{\mathrm{gd}}$	Gate-Drain Charge	ID-JUA		16			

Note: 1: Pulse test; pulse width  $\leq 300$ ns, duty cycle  $\leq 2\%$ .

<sup>2:</sup> Guaranteed by design, not subject to production testing.

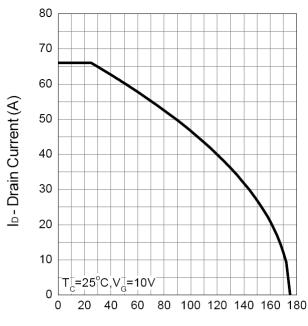
# **Typical Characteristics**

### Power Dissipation



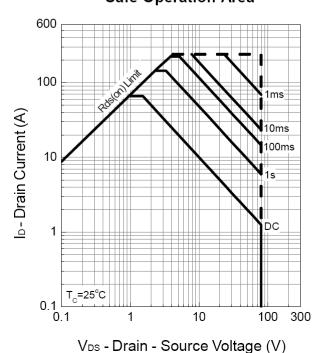
 $T_j$ - Junction Temperature (°C)

#### **Drain Current**

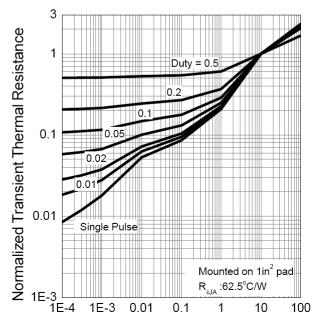


T<sub>j</sub>- Junction Temperature (°C)

#### Safe Operation Area



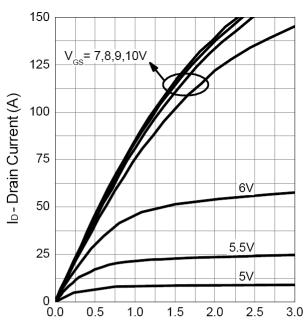
#### Thermal Transient Impedance



Square Wave Pulse Duration (sec)

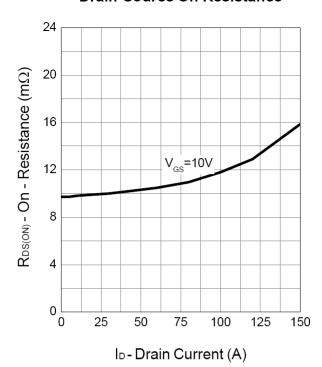
## **Typical Characteristics (Cont.)**

#### **Output Characteristics**

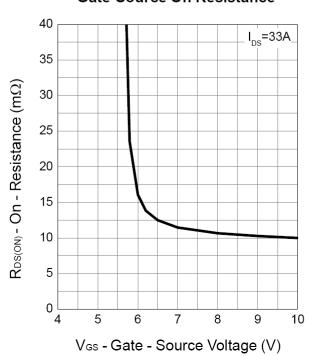


V<sub>DS</sub> - Drain - Source Voltage (V)

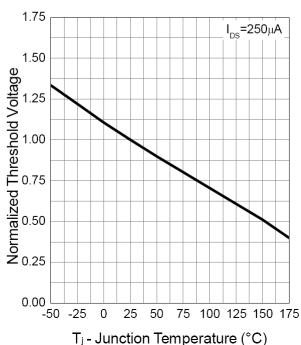
#### **Drain-Source On Resistance**



**Gate-Source On Resistance** 



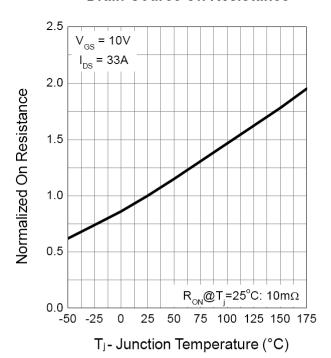
**Gate Threshold Voltage** 



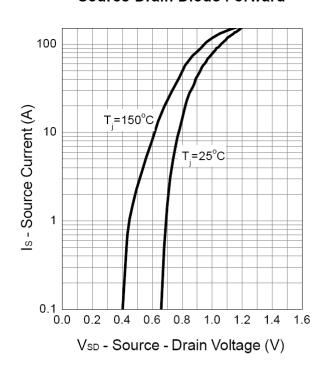
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## **Typical Characteristics (Cont.)**

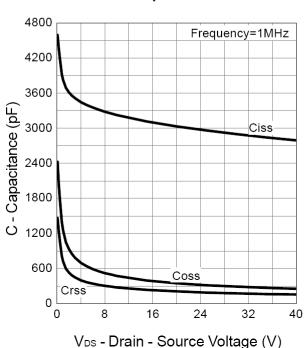
#### **Drain-Source On Resistance**



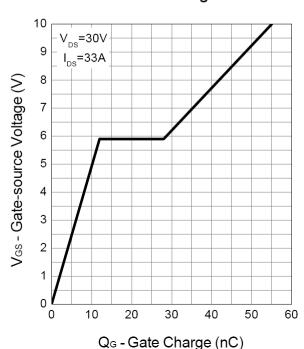
#### **Source-Drain Diode Forward**







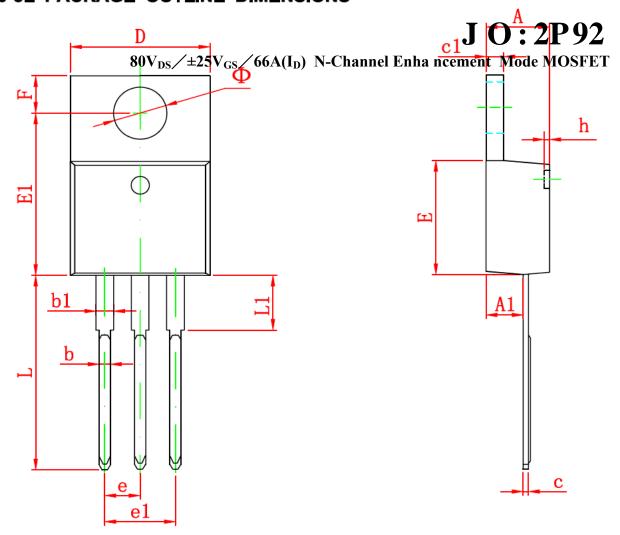
Gate Charge



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## **TO-220-3L PACKAGE OUTLINE DIMENSIONS**



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
Syllibol	Min	Max	Min	Max	
Α	4.470	4.670	0.176	0.184	
A1	2.520	2.820	0.099	0.111	
b	0.710	0.910	0.028	0.036	
b1	1.170	1.370	0.046	0.054	
С	0.310	0.530	0.012	0.021	
c1	1.170	1.370	0.046	0.054	
D	10.010	10.310	0.394	0.406	
Е	8.500	8.900	0.335	0.350	
E1	12.060	12.460	0.475	0.491	
е	2.540	) TYP	0.100 TYP		
e1	4.980	5.180	0.196	0.204	
F	2.590	2.890	0.102	0.114	
h	0.000	0.300	0.000	0.012	
L	13.400	13.800	0.528	0.543	
L1	3.560	3.960	0.140	0.156	
Ф	3.735	3.935	0.147	0.155	

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